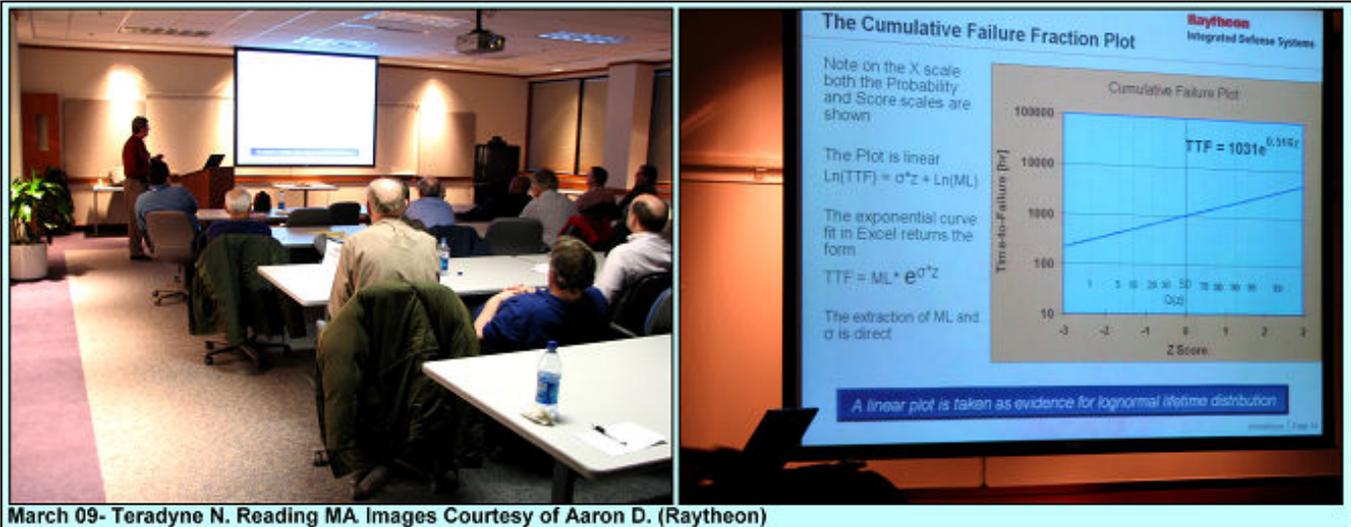


**IEEE Reliability Society Newsletter Submission
from the Joint Section Chapter
(Boston - New Hampshire - Providence)
March 2009 - April 2010**

Greetings! The IEEE Reliability Joint Section Chapter (Boston - New Hampshire - Providence) has held several meetings since our last newsletter entry. The AdCom is currently reviewing the potential speakers & meetings for the up-coming 2010-2011 meeting season, including Reliability track support for the 58th NEQC Conference!



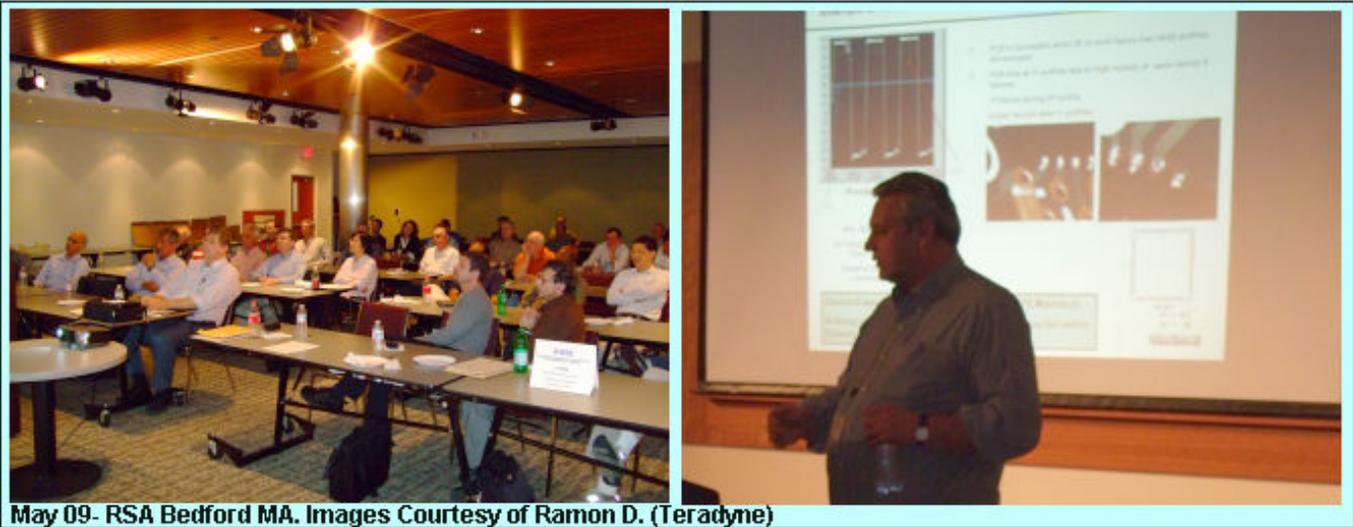
March 09- Teradyne N. Reading MA. Images Courtesy of Aaron D. (Raytheon)

March 2009: Michael Benedek Sr. Principal Engineer & Reliability team lead from Raytheon RF Components presented "*Microwave Device Reliability Characterization-The Mechanics of Life Test Execution and Analysis*". This meeting was held on Tuesday March 10th at Teradyne Inc. North Reading, MA campus with a total of 36 members and guests.



April 09- EMC Hopkinton MA. Images Courtesy of Ramon D. (Teradyne)

April 2009: on Wednesday the 15th we held our meeting at EMC Corporation Headquarters in Hopkinton, MA. IEEE Fellow Dr. Shubu Mukherjee who is a Principal Engineer at Intel Corporation presented "*Super-Linear Increase in Soft Error Rate from Doubling the Cache Size: Bug or Phenomenon?*" Dr. Mukherjee reviewed detectable unrecoverable errors experienced in the expansion of processor L2 Cache with 31 members and guests.



May 09- RSA Bedford MA. Images Courtesy of Ramon D. (Teradyne)

May 2009: Romano Anecchiarico, Operations Reliability Lead from Teradyne, Inc. presented “*Effective Environmental Test Technology in New Product Introduction (NPI)*”. This meeting was held on Wednesday May 13th at RSA, the Security Division of EMC, in Bedford, MA with 43 members and guests.



June 09- Teradyne N. Reading MA Images Courtesy of Aaron D. (Raytheon)

The June 09 meeting at Teradyne N. Reading, (right image) David Casper, IEEE Providence, RI Section Chair, Ramon De la Cruz, IEEE Reliability Society Joint Section Chapter Chair, Eddie Robins, Secretary, Aaron Dermarderosian, vice chair and Jim Anderson, IEEE New Hampshire Section Chair.

June 2009: on Tuesday the 16th we held our meeting at Teradyne Inc. North Reading, MA campus. Donald V. Trenholm founder and CEO of Custom Analytical Services, Salem, NH presented “*Effective Techniques for the Identification of Counterfeit Electronics*”. Don’s presentation included typical examples of the creative methods used by device counterfeiters and gave an overview of methods for spotting suspect parts to 45 members and guests which included the Providence, RI and New Hampshire Section Chairs.



July 09 TDC- Benchmark Electronics Hudson N.H. Images Courtesy of Aaron D. (Raytheon)

July 2009: On Tuesday the 14th the IEEE Reliability Society Joint Section Chapter held a joint meeting with the SMTA which included a tour of Benchmark Electronics, Hudson, NH Product Assurance and Failure Analysis Laboratory and technical presentations by experts from U-Mass Lowell, Benchmark and EMC Corporation.

- **Greg Morose, New England Lead Free Electronics Consortium, University of Massachusetts Lowell** presented *“Long Term Reliability Analysis of Lead Free and Halogen Free Electronic Assemblies”*.
- **Deb Fragoza, EMC Corporation, Hopkinton MA, Bob Farrell and Paul Bodmer, Benchmark Electronics, Hudson NH** presented *“Evaluation of a RoHS Compliant Nanotechnology Printed Circuit Board Surface Finish”*.
- **Bob Farrell, Benchmark Electronics, Hudson NH,** hosted a live Demonstration of a Pb-free Through-hole Rework Technique Used in Phase IV to Minimize Copper Dissolution.

64 members and guests in attendance were treated to a summer BBQ Dinner.

09-10 Meetings & Events: (Sept 09 - Apr 10)



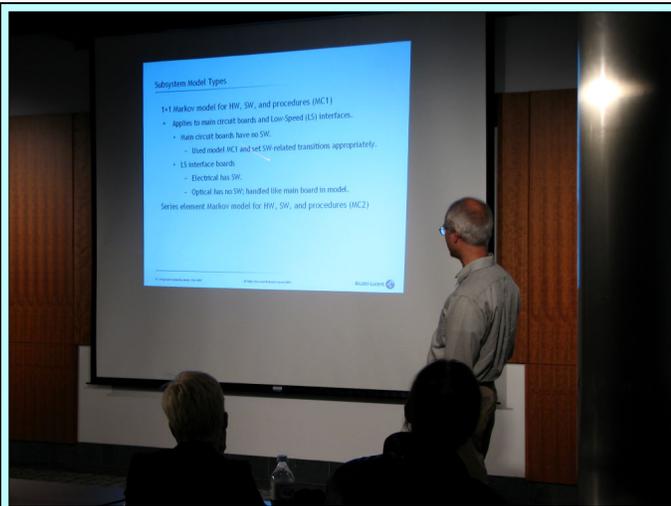
Sept 09- Meeting @ RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

September 2009: our first meeting of the 09-10 season was held on Wednesday, Sept 9 at RSA, the Security Division of EMC, Bedford, MA. Frank Andres, Senior Customer Technical Support Engineer for Alpha Metals Inc/Cookson Electronics presented *“SMT and Wave Soldering Technology Drivers and Their Influence on Alloy Selection”* to 30 members and guests.



Oct 09- Meeting @ RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

October 2009: the IEEE Reliability Society Joint Section Chapter held a joint meeting with the Northeast Chapter of the ESD Association at RSA, the Security Division of EMC, Bedford, MA on Wednesday, October 14th. Ted Dangelmayer, Chair, Dangelmayer Associates presented “*Common ESD Myths and Pitfalls of ESD Measurement Instruments*” to 45 members and guests.



Nov 09- Meeting @ RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

November 2009: Philip Scarf, Member of the Technical Staff, Alcatel-Lucent presented “*A New Approach to System-Availability Analysis: An Integrated Hardware, Software, and Procedures Model*” at our meeting held on Wednesday November 11 at RSA, the Security Division of EMC, Bedford, MA. 35 members and guests attended this event.



Dec 2009 Annual past chairs & dinner monthly meeting; Images Courtesy of Aaron D. (Raytheon)



Dec 09- Meeting @ RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

December 2009: On December 9th we held our annual chapter past chairs & dinner meeting at RSA, the Security Division of EMC, Bedford, MA. A chapter brief was presented highlighting chapter meetings & activities through 2009 and the results of our annual Chapter Officer elections.

For the 2010 term Ramon De la Cruz (Teradyne) was re-elected as chapter Chair, Aaron DerMarderosian Jr. (Raytheon) re-elected as chapter vice-chair, Don Markuson (Sierra Atlantic) was re-elected as chapter Treasurer & Shivarajiv Somisetty (M/A-COM) was elected to chapter Secretary. For our annual dinner meeting, we had several past chapter chairs in attendance. Amongst those recognized for their contributions were:

- Avery Hevesh: Chair 1969-1970**
- Don Simpson: Chair, 1973 – 1974 & 1989 - 1990**
- Don Markuson: Chair, 1990 - 1991 & 1995 – 1996**
- Brian McQuillan: Chair, 1994 – 1995**
- Giora Kedem: Chair, 1997 - 1999**
- Jim Fahy: Chair, 1999 - 2000 & 2004**
- Jeff Clark: Chair, 2000 - 2003 & 2005**
- Aaron DerMarderosian Jr.: Chair, 2006 – 2008**
- Ramon De la Cruz: Chair, 2009**

Our featured guest speakers Giora Kedem, Reliability Consultant, Daniel Wilder, Consultant, Hardware Engineer and Carl Nickerson, Software Engineer, all from RSA, the Security Division of EMC, Bedford, MA., presented “100X Token Reliability Improvement”, where they described the best practices used by their reliability group to improve the reliability of some of RSA’s most popular products. We had a total of 31 members & guests at this meeting.



Jan 10- Meeting @ Teradyne North Reading, MA. Images Courtesy of Aaron D. (Raytheon)

January 2010: we held our first meeting of 2010 on Wednesday, January 13th at Teradyne Inc. North Reading, MA. Dave Dwyer, BAE Systems presented “Improvements in Automated Reliability Growth Plotting and Estimations” to 45 members and guests.

February 2010: our meeting scheduled for February 10th was canceled, due to winter weather.



March 10- Meeting @ RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

March 2010: Don Restiano and Liz Markewicz, Raytheon Company presented “Risk Management: Pro-active Principles for Project Success” on Wednesday, March 10th at RSA, the Security Division of EMC, Bedford, MA. 39 members and guests attended this event.



April 10- Meeting @RSA, the Security division of EMC, Bedford MA. Images Courtesy of Aaron D. (Raytheon)

April 2010: on Wednesday, April 14th we held our meeting at RSA, the Security Division of EMC, Bedford, MA. Prof. David I. Heimann, Reliability Engineer, presented “*A Bipartite Empirically Oriented Metrics Process for Agile Software Development*” to 22 members and guests.

Upcoming meetings & Events:

May 2010: Keith Donaldson, Engineered Materials, Inc. will present on the 12th “*How carbon footprints, green initiatives and reliability work together, or against each other?*” at RSA, the Security Division of EMC, Bedford, MA.

June 2010: IEEE Reliability Society Standards Committee Chair, Lou Gullo, Raytheon – Integrated Defense Systems (IDC) Seapower Capability Center (SCC) in Portsmouth, RI, will present “*IEEE Reliability Society Standards Status and Descriptions*”. This meeting will be held June 9th at EMC Corporation Headquarters in Hopkinton, MA. Registration for this event is open on the Boston Reliability chapter website and will close on Friday, June 4, 2010.

October 2010: The Joint section chapter will support the Reliability Track for the 58th NEQC Conference. This will be the 3rd consecutive conference where the Reliability chapter has chaired the track at this bi-annual event.

Please check our website periodically for updates on upcoming events!

<http://www.ieee.org/bostonrel>

If you would like to present a reliability based topic at a future meeting, have meeting topic suggestions or ideas about how to improve our meetings, we want to hear from you! Please

send an e-mail to any of the AdCom members or go to our website and Click on: [Suggest a Monthly Meeting Topic](#).

To participate or provide input to chapter technology development activities, sign up to become a TDC committee participant using our website. Click on: [Join Technology Development](#).

You can also be added to the chapter e-notice distribution via our website, click on: [Join our E-Mail Distribution List](#) or send a request to: dermarderosiana@ieee.org (Vice-chair, notices & registration).

Best Regards,

Ramon De la Cruz. - Chair, Reliability Joint Section Chapter
(Boston - New Hampshire - Providence)